

Notice of References Cited	Application/Control No. 10/039,383	Applicant(s)/Patent Under Reexamination CHU ET AL.	
	Examiner S. Devi, Ph.D.	Art Unit 1645	Page 1 of 1

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*	C	US-6,585,981	07-2003	Pijoan, Carlos	424/264.1
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	U	Martinon et al. In: Proc. 15th IPVS Congress. (Ed) Stanley Done et al. Birmingham, England, 5-9 July 1998, page 284. ✓
	V	Reynaud et al. In: Proc. 15th IPVS Congress. (Ed) Stanley Done et al. Birmingham, England, 5-9 July 1998, page 150. ✓
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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